BS IEC 62951-4:2019

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Semiconductor devices - Flexible and stretchable semiconductor devices

Part 4: Fatigue evaluation for flexible conductive thin film on the substrate for flexible semiconductor devices

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National foreword

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The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its secretary.

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Semiconductor devices – Flexible and stretchable semiconductor devices – Part 4: Fatigue evaluation for flexible conductive thin film on the substrate for flexible semiconductor devices

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SEMICONDUCTOR DEVICES – FLEXIBLE AND STRETCHABLE SEMICONDUCTOR DEVICES –

Part 4: Fatigue evaluation for flexible conductive thin film on the substrate for flexible semiconductor devices

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Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

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